



Terahertz and Far Infrared Pulsed Devices and Systems

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Deadline for manuscript
submissions:

closed (31 May 2019)

Message from the Guest Editors

Dear Colleague,

Pulsed Terahertz (100 GHz- 10 THz) and far infrared (FIR up to 30 THz) systems and devices have been, and still are, a major driver of the research field. This Special Issue aims for providing an overview about latest research and developments of pulsed THz and FIR devices and systems including, but not limited to, the following topics:

- Sources & detectors
- System concepts (e.g. ASOPS, ECOPS, OSCAT, ABCD)
- New materials and concepts for pulsed THz/FIR devices
- Non-destructive testing including thickness analysis
- Broadband spectroscopy, algorithms for material parameter extraction
- 2D and 3D hyperspectral imaging
- Fundamental research including nonlinear effects in matter

Further information:

[mdpi.com/journal/applsci/special_issues/Terahertz_Far_Infrared](https://www.mdpi.com/journal/applsci/special_issues/Terahertz_Far_Infrared)

We are looking forward to your contribution!

Best regards,

Prof. Dr. Sascha Preu

Prof. Dr. Jan Balzer

Guest Editors



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Special Issue



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Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

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